

CDM Tester

Charged Device Model Tester

HED-C5000R

- Built-in automatic Humidity control & N2 Enclosed chamber
- Fully universal size/configuration DUT
- Conforms to ESDA_JEDEC JS-002(AEC), JEITA standards



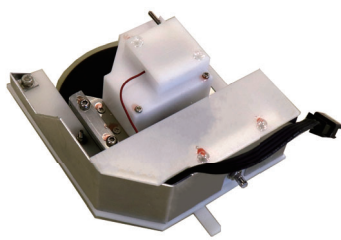
Hanwa Electronic Ind. Co., Ltd.

Specification

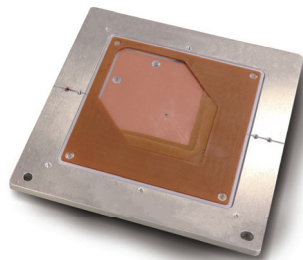
Built-in automatic Humidity control & N2 Enclosed chamber.
Fully universal size/configuration DUT.
Automatic CDM-waveform capture system.

Model	HED-C5000R
Test model	ESDA JEDEC JS-002(AEC), JEITA
Test Capability	1024 Pins or Higher
Test voltage	0 to +/-4000V
Step voltage	5V
Zap number	1 to 100 times
Interval time	0 to 10s
Test voltage accuracy	1%+/-10V
Power source	100-240V/2A, 50/60Hz
Outer dimensions	575mm(W)×400mm(D)×300mm(H)
Weight	40Kg
OS	Windows

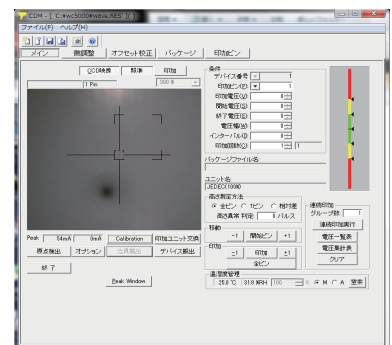
Operability



Zap Unit



Device mounting jig



Main Screen

Features

Applicable Standards

ESDA JEDEC JS-002(AEC), JEITA standards

Capacitance measurement (option)

Capacity of each pin of the device is measured.

The data can be saved in text file

Wide Motion Test area(80mm x 200mm)

Test voltage range: 0 to +/-4000V (+/-5V steps)

Real time waveform capture function

If you have any questions, please contact us.



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■ Agency